

Search Notes

Application/Control No.

10/511,451

Examiner

Karen Mash

Applicant(s)/Patent under
Reexamination

TAKENAKA ET AL.

Art Unit

2837

SEARCHED

Class	Subclass	Date	Examiner
318	568.11	9/7/02	Xm
	568.12	/	
	568.15	/	
	568.16		
	568.17	/	
	568.18		
	568.22		
	568.25		
901	1		
901	9		
700	63		
700	245	✓	

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner